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	Substitute Form PTO-1449 (Modified)	U.S. Department of Commerce Patent and Trademark Office	Attorney's Docket No. 10559-893001	Application No. 10/789,670
Information Disclosure Statement by Applicant		Applicant Arun Ramamoorthy et al.		
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	(37 CFR \$1 98(b))		February 27, 2004	1724

			U.S. Pate	ent Documents			
Examiner Initial	Desig. ID	Document Number	Publication Date	Patentee	Class	Subclass	Filing Date If Appropriate
	AA						
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Initial	ID	Number	Date	Patent Office	Class	Subclass	Yes	No
	AL							
	AM							
	AN							
	AO							
	AP							

(Other D	ocuments (include Author, Title, Date, and Place of Publication)
Examiner	Desig.	
Initial	ID	Document
	AQ	Chauhan, M.M., et al., "Photoresist Outgassing in EUV", 2000 March Meeting: Bulletin of the American Physical Society, 45(1):563, abstract #L36.112, March 2000.
	AR	Moors, R., et al., "Electrostatic mask protection for extreme ultraviolet lithography", <i>Journal of Vacuum Science & Technology B: Microelectronics and Nanometer Structures</i> , 20(1):316-320, Jan/Feb 2002.
	AS	
	AT	

Examiner Signature	Date Considered
EXAMINER: Initials citation considered. Draw line through citation if no	t in conformance and not considered. Include copy of this form with
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